5th IEEE International Workshop on Silicon Debug and Diagnosis 2008

Final Program

Day 1 : April 30th 2007		
4:00 PM	4:15 PM	***Opening remarks***
• **Fidel Muradali** (National Semiconductor) • **Bart Vermeulen** (NXP Semiconductors)		
4:15 PM	5:30 PM	***Paper Session 1*** Chair: Ismed Hartanto (Xilinx)
• "*Silicon debug of timing failures with debug-oriented scan test patterns*", Christian Burmer[1], **Ruifeng Guo**[2], Wu-Tung Cheng[2], Xijiang Lin[2], Brady Benware[2] ([1]Infineon, [2]Mentor Graphics)		
• "*Targeting Leakage Constraints during ATPG*", Görschwin Fey[1,2], **Satoshi Komatsu**[1], Yasuo Furukawa[3], Masahiro Fujita[1] ([1]University of Tokyo, [2]University of Bremen, [3]Advantest)		
• "*An Industrial Case Study of Diagnosing Randomly Distributed Chain Defects for Process and Yield Improvement*", Gunaseelan Ponnuvel[1], Mark Grosset[1], **Yu Huang**[2], Wu Yang[2] ([1]Conexant System, [2]Mentor Graphics)		
5:30 PM	5:45 PM	***Break***
5:45 PM	5:50 PM	**Soapbox - Haluk Konuk** (Broadcom)
5:50 PM	6:40 PM	***Special Session 1*** Chair: Teresa McLaurin (ARM)
• "*IEEE P1687 Update – Inside the Chip*", **Al Crouch** (Asset Intertech) • "*Post silicon debug and validation of a multi-million gate high-definition digital TV controller*", **Miron Abramovici** (DAFCA)		
7:00 PM	9:00 PM	***Social Event***

Day 2 : May 1st 2007		
8:00 AM	8:45 AM	**Keynote** Chair: Bart Vermeulen (NXP Semiconductors)
• **Nitin Deo** (Cadence Design Systems)		
8:45 AM	10:00 AM	***Paper Session 2*** Chair: Mike Ricchetti (AMD)
• "*An Automated Software Solution to Silicon Debug*", Yu-Shen Yang[1], Andreas Veneris[1], **Nicola Nicolici**[2] ([1]University of Toronto, [2]McMaster University) • "*Methodology for Hardware/Software co-debug*", **Gertjan Arnoldussen**[1], Hans Kok[2] ([1]Philips, [2]NXP Semiconductors) • "*A New Approach for Capturing Trace Data from SoCs*", **Alexander Weiss**[1], Christian Hochberger[2] ([1]Accemic GmbH, [2]Univ. of Technology Dresden)		
10:00 AM	10:30 AM	***Break***

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10:30 AM	12:00 PM	***Paper Session 3*** Chair: Davide Appello – STMicroelectronics
• "*Rapid Navigation for Semiconductor Failure Analysis Without Requiring Layout vs. Schematic (LVS) Information*", **Roger Nicholson**, Hitesh Suri (DCG Systems)		
• "*A Learning of Process Interacted Silicon Debug of UltraSPARC T2 Microprocessor*", **Poh-Joo Tan** (Sun Microsystems)		
• "*Hardware/Software Co-Design/Execution Approach to Silicon Debug and Diagnosis*", **Masahiro Fujita**, Hiroaki Yoshida Satoshi Morishita (University of Tokyo) (S)		
• "*An Efficient and Cost Effective Methodology for Post Silicon Test Pattern Generation*", **Andy Chang Seow Pin**, Lee Khim-Hou (Infineon) (S)		
12:00 PM	1:30 PM	***Lunch***
1:30 PM	2:20 PM	***Special Session 2*** Chair: Nicola Nicolici (McMaster Univ.)
• "*The role that ATE can play in Silicon Debug and Diagnosis*", **Don Blair** (Verigy)		
• "*Boosting yield learning by leveraging advanced design automation during failure analysis*", **Simona Pappalardo** (ST Microelectronics)		
2:20 PM	3:35 PM	***Paper Session 4*** Kazumi Hatayama (STARC)
• "*A case study on SoC low-cost Silicon Debug and Diagnosis*", D. Appello[1], M. Rotigni[1], V. Tancorre[1], P. Bernadi[2], **M. Grosso**[2], M. Sonza Reorda[2], ([1]ST Microelectronics, [2]Politecnico Torino) • "*Study on Hardware Overhead Reduction for Memory BIST*", Kentaro Osawa[1], Masayuki Arai[1], **Kazuhiko Iwasaki**[1], Michinobu Nakao[2], ([1]Tokyo Metropolitan University, [2]Renesas Technology) • "*A Novel Hardware Description language for efficient debug and diagnosis of digital circuits*", **Michele Portolan**[1], Suresh Goyal[1], Brad Van Treuren[2], Chen-Huan Chiang[2], Tapan Chakraborty[2] and Tom Cook[2] ([1]Bell Labs Ireland, [2]Alcatel-Lucent Bell Labs)		
3:35 PM	3:50 PM	***Break***
3:50 PM	3:55 PM	**Soapbox - Doug Josephson** (Intel)
3:55 PM	4:45 PM	**Special Session 3** Chair: Teresa McLaurin (ARM)
• "*Innovation from Debug: Creatively Reducing a Ground Loop*", **Hugh Weinrich** (National Semiconductor)		
• "Debug and Diagnostic Data for Yield Learning", **Jay Orbon** (Verigy)		
4:45 PM	5:00 PM	***Wrap-up***
• **Fidel Muradali** (National Semiconductor) • **Bart Vermeulen** (NXP Semiconductors)		

(S) = Short paper, **bold** = Designated Speaker